



# TECHNICAL SPECIFICATION



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## Photovoltaic devices – Part 13: Electroluminescence of photovoltaic modules

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

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## CONTENTS

FOREWORD.....	4
1 Scope.....	6
2 Normative references .....	6
3 Terms and definitions .....	6
4 Imaging .....	7
4.1 Apparatus .....	7
4.1.1 Electroluminescence imaging camera .....	7
4.1.2 Dark room imaging studio or environment.....	9
4.1.3 Power supply.....	10
4.1.4 Computer interface with camera and power supply for image capture .....	11
4.1.5 Image processing and displaying software.....	11
4.1.6 Safety and handling .....	12
4.2 Procedure .....	12
4.2.1 Camera settings and positioning .....	12
4.2.2 Camera settings .....	13
4.2.3 Sharpness determination and classification .....	14
4.2.4 Imaging .....	16
4.2.5 Image correction.....	17
4.3 Image signal-to-noise ratio.....	18
4.3.1 General .....	18
4.3.2 Imaging procedure.....	18
4.3.3 Analysis.....	18
4.3.4 SNR criteria.....	19
5 Evaluation of EL images .....	20
5.1 Principles of electroluminescence .....	20
5.2 Image interpretation.....	21
5.2.1 Series resistance .....	21
5.2.2 Minority carrier lifetime and diffusion length.....	21
5.2.3 Shunt resistance.....	21
5.2.4 Assignment of root cause .....	21
5.3 Histogram-based analysis of the electroluminescence signal .....	21
5.3.1 General .....	21
5.3.2 Image information .....	22
5.3.3 Bias current effects.....	22
5.3.4 Analysis of intensity distributions .....	22
5.3.5 Variance .....	22
5.3.6 Kurtosis .....	22
5.3.7 Skewness .....	22
5.3.8 Pixel (or area)-weighted electroluminescence relative to an ideal module .....	22
6 Reporting.....	22
Annex A (normative) Procedures for image correction.....	24
A.1 Dark current and stray light removal.....	24
A.2 Vignetting .....	24
A.2.1 Vignetting correction.....	24
A.2.2 Vignetting as a function of angle from the optical axis.....	24
A.2.3 Correction for vignetting .....	24

Annex B (informative) Focus .....	26
B.1 General.....	26
B.2 Application of the Tenengrad function and Sobel operator .....	26
Annex C (normative) Quantifying solar cell cracks in photovoltaic modules .....	27
C.1 General.....	27
C.2 Cell crack modes .....	27
C.3 Basis of cell damage quantification .....	28
C.4 Procedure .....	30
Annex D (informative) .....	32
D.1 Qualitative interpretation of electroluminescence images crystalline Si PV modules .....	32
D.2 Qualitative interpretation of electroluminescence images in thin-film PV modules .....	36
Bibliography.....	39
Figure 1 – Various semiconductor detector materials and their absolute spectral response [1].....	8
Figure 2 – Electroluminescence emission spectra for (a) Si, (b) ZnO/CdS/Cu(In,Ga)Se <sub>2</sub> (CIGS) [2], and (c) CdS/CdTe [3].....	8
Figure 3 – Example of frame subtraction given in Figure 3a) to Figure 3c), with images taken in ideal dark room conditions given in Figure 3d).....	12
Figure 4 – EL image with introduced two edges using aluminum tape .....	15
Figure 5 – Edge gradient image <b>GEdge</b> from the Figure 4 EL image's first derivative in orthogonal direction <b>G<sub>x,y</sub></b> .....	15
Figure 6 – Excerpt of the EL image of Figure 4 and plot of image intensity values along line <b>L<sub>2</sub></b> .....	15
Figure 7 – Images of regions of multicrystalline silicon solar cells with three <b>SNR<sub>50</sub></b> values as labeled.....	20
Figure 8 – Emission of light ( <b>hν</b> ) associated with the electroluminescence process in solar cells of PV modules.....	20
Figure 9 – Scheme for labeling position of cells in a module viewed from the light-facing side according to coordinates ( <b>i,j</b> ) in portrait orientation (a) or rotated into landscape orientation (b), which shall be indicated if applicable .....	23
Figure B.1 – EL image of a solar cell (left) and a silicon module (right) .....	26
Figure C.1 – Single cell region of a module with $0,1 \times I_{SC}$ applied showing crack types, as labeled .....	27
Figure C.2 – Example of normalized EL intensity histograms calculated from the EL images of modules with various levels of cell cracking and resulting power degradation, indicated by <b>P<sub>max</sub></b> .....	29
Figure C.3 – Example of quantifying solar cell cracks in photovoltaic modules: (a) EL image produced with $0,1 \cdot I_{SC}$ forward bias current, and (b) image of regions considered damaged.....	31
Table 1 – Detectors and their applicable wavelengths.....	7
Table 2 – Sharpness classes, examples of images meeting the criteria of the classes, and examples of distinguishable features.....	16
Table D.1 – Descriptions of observables, features, and known causes, along with electroluminescence images for crystalline Si modules .....	32
Table D.2 – Descriptions of observables, features, and known causes, along with electroluminescence images for thin-film modules .....	36

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### PHOTOVOLTAIC DEVICES –

### Part 13: Electroluminescence of photovoltaic modules

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Technical specifications are subject to review within three years of publication to decide whether they can be transformed into International Standards.

IEC TS 60904-13, which is a technical specification, has been prepared by IEC technical committee 82: Solar photovoltaic energy systems.

The text of this technical specification is based on the following documents:

Enquiry draft	Report on voting
82/1292/DTS	82/1424/RVDTS

Full information on the voting for the approval of this technical specification can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60904 series, published under the general title *Photovoltaic devices*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

## PHOTOVOLTAIC DEVICES –

### Part 13: Electroluminescence of photovoltaic modules

#### 1 Scope

This part of IEC 60904 specifies methods to:

- a) capture electroluminescence images of photovoltaic modules,
- b) process images to obtain metrics about the images taken in quantitative terms, and
- c) provide guidance to qualitatively interpret the images for features in the image that are observed.

This document is applicable to PV modules measured with a power supply that places the cells in the modules in forward bias.

#### 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC TS 61836:2016, *Solar photovoltaic energy systems – Terms, definitions and symbols*